



In re Application for:

Examiner: Kerveros, James C.

Art Group: 2858

For: METHOD AND APPARATUS FOR  
SUB-MICRON IMAGING AND PROBING ON  
PROBE STATION

Attn: Official Draftsman  
Assistant Commissioner for Patents  
Washington, D.C. 20231

Enclosed herewith for filing in the above-identified U.S. patent application are the formal drawings, Figures 1, 2, 3, 4, and 5 (5) sheets.

BLAKELY SOKOLOFF TAYLOR & ZAFMAN, LLP

James Y. Go  
Reg. No. 40,621

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner of Patents and Trademarks, Washington, D.C. 20231, on 2-13-02

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